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| Notice of References Cited | Application/Control No. 10/082,009 | Applicant(s)/Patent Under Reexamination SHIH ET AL. | |
| | Examiner Alexander Markoff | Art Unit 1746 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-6,147,002 | 11-2000 | Kneer, Emil Anton | 438/692 |
| | B | US-6,153,043 | 11-2000 | Edelstein et al. | 156/345.12 |
| | C | US-6,162,301 | 12-2000 | Zhang et al. | 134/3 |
| | D | US-6,251,787 | 06-2001 | Edelstein et al. | 438/692 |
| | E | US-6,323,131 | 11-2001 | Obeng et al. | 438/687 |
| | F | US-6,376,345 | 04-2002 | Ohashi et al. | 438/542 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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